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Application No.	Applicant(s)	
10/042,831	LEE ET AL.	,
Examiner	Art Unit	
Sean Reilly	2153	

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SEARCHED			
Class	Subclass	Date	Examiner
709	204, 205, 206, 207	4/14/2005	SR
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
See attached EAST search.	4/14/2005	SR
Consulted w/ Primary Examiner Dinh	4/15/2005	SR
Searched ACM and IEEE NPL databases.	4/15/2005	SR
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